

## **Search Notes**



**Application/Control No.**

10/089,409

Examiner

TAN X. DINH

**Applicant(s)/Patent under  
Reexamination**

AIKOH ET AL.

## **Art Unit**

2653

**SEARCHED**

## **SEARCH NOTES (INCLUDING SEARCH STRATEGY)**

## **INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner